Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
09/382,371	PHILYAW ET AL.
Examiner	Art Unit
Hai V. Nguyen	2142

	SEAR	CHED	
Class	Subclass	Date	Examiner
705	26	4/29/2006	HN
235	472.03	4/29/2006	HN

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
		., .,	

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST Saerch Updated ( USPGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TBD) (see search history printout)	4/29/2006	HN
ILimited classified search : 705/26; 235/472.03 (see search history printout)	4/29/2006	HN
		_

